

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HEINE ET AL.	
		10/712,762	Examiner	Art Unit
		Mark Ruthkosky	1745	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0234632	12-2003	Fang, Jang-Chung	320/110
	B	US-5,764,033	06-1998	Tamai, Mikitaka	320/132
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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